Search Notes				

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/722,600	IKEDA ET AL.	
	Examiner	Art Unit	
	Rita Leykin	2837	

Rita Leykin

	SEARCHED		
Class	Subclass	Date	Examiner
318	560	4/27/2006	R.L.
	606		
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SEARCH NO (INCLUDING SEARCH)
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